



DMG4822SSD

DUAL N-CHANNEL ENHANCEMENT MODE MOSFET

Product Summary

V _{(BR)DSS}	R _{DS(ON)} max	I _D max T _A = +25°C
30V	20mΩ @ V _{GS} = 10V	10A

Description

This MOSFET has been designed to minimize the on-state resistance $(R_{DS(on)})$ and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

Applications

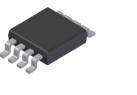
- General Purpose Interfacing Switch
- Power Management Functions
- DC-DC Converters
- Analog Switch

Features and Benefits

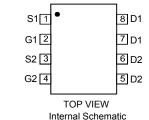
- Low On-Resistance
- Low Input Capacitance
- Low Input/Output leakage
- Low Gate ResistanceFast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

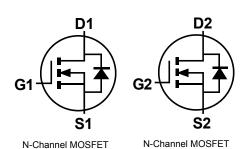
Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish NiPdAu over Copper leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.072 grams (approximate)



Top View





Ordering Information (Note 4)

_		
Part Number	Case	Packaging
DMG4822SSD-13	SO-8	2,500/Tape & Reel

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.

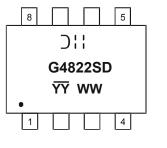
2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.

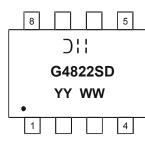
3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information

Notes:





Chengdu A/T Site

Shanghai A/T Site

);; = Manufacturer's Marking
G4822SD = Product Type Marking Code
YYWW = Date Code Marking
YY or YY = Year (ex: 13 = 2013)
WW = Week (01 - 53)
YY = Date Code Marking for SAT (Shanghai Assembly/ Test site)
YY = Date Code Marking for CAT (Chengdu Assembly/ Test site)



Maximum Ratings @T_A = 25°C unless otherwise specified

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V _{DSS}	30	V
Gate-Source Voltage			V _{GSS}	±25	V
Continuous Drain Current (Note 5) V_{GS} = 10V	Steady State	T _A = +25°C T _A = +85°C	ID	10 6.6	А
Pulsed Drain Current (Note 6)			I _{DM}	60	А
Avalanche Current (Note 7 & 8)			I _{AR}	1.68	А
Repetitive Avalanche Energy L= 0.3mH (Note 7 & 8)			E _{AR}	12.8	mJ

Thermal Characteristics @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 5)	PD	1.42	W
Thermal Resistance, Junction to Ambient (Note 5)	R _{0JA}	88.4	°C/W
Operating and Storage Temperature Range	T _{J,} T _{STG}	-55 to +150	°C

Electrical Characteristics @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 9)							
Drain-Source Breakdown Voltage	BV _{DSS}	30	-	-	V	$V_{GS} = 0V, I_{D} = 250 \mu A$	
Zero Gate Voltage Drain Current	IDSS	-	-	1	μA	V _{DS} = 30V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	-	-	±100	nA	$V_{GS} = \pm 25 V, V_{DS} = 0 V$	
ON CHARACTERISTICS (Note 9)							
Gate Threshold Voltage	V _{GS(th)}	1	-	3	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	
Static Drain-Source On-Resistance	D	-	13.4	20	mΩ	V _{GS} = 10V, I _D = 8.5A	
	R _{DS (ON)}	-	19.5	31	11122	V_{GS} = 4.5V, I _D = 6A	
Forward Transfer Admittance	Y _{fs}	-	20	-	mS	V _{DS} = 5V, I _D = 8.5A	
Diode Forward Voltage	V _{SD}	-	0.4	1.0	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 10)							
Input Capacitance	Ciss	-	478.9	-	рF		
Output Capacitance	Coss	-	96.7	-	рF	$-V_{DS} = 16V, V_{GS} = 0V,$ -f = 1MHz	
Reverse Transfer Capacitance	C _{rss}	-	61.4	-	рF		
Gate resistance	Rg		1.1		Ω	V_{DS} = 0V, V_{GS} = 0V, f = 1MHz	
Total Gate Charge (V _{GS} = 4.5V)	Qg		5	-	nC		
Total Gate Charge (V _{GS} = 10V)	Qg	-	10.5	-	nC	$V_{GS} = 10V, V_{DS} = 15V,$	
Gate-Source Charge	Q _{gs}	-	1.8	-	nC	− I _D =8.5A	
Gate-Drain Charge	Q _{gd}	-	1.6	-	nC		
Turn-On Delay Time	t _{D(on)}	-	2.9	-	ns		
Turn-On Rise Time	tr	-	7.9	-	ns	V _{DS} = 15V, V _{GS} = 10V,	
Turn-Off Delay Time	t _{D(off)}	-	14.6	-	ns	$R_{L} = 1.8\Omega, R_{G} = 3\Omega,$	
Turn-Off Fall Time	t _f	-	3.1	-	ns		

Notes: 5. Device mounted on FR-4 PCB, with minimum recommended pad layout.

6. Device mounted on minimum recommended pad layout test board, 10µs pulse duty cycle = 1%

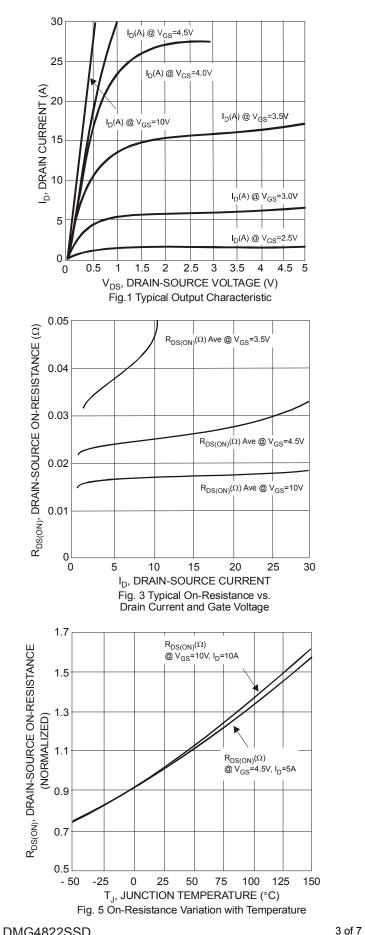
7. Repetitive rating, pulse width limited by junction temperature.

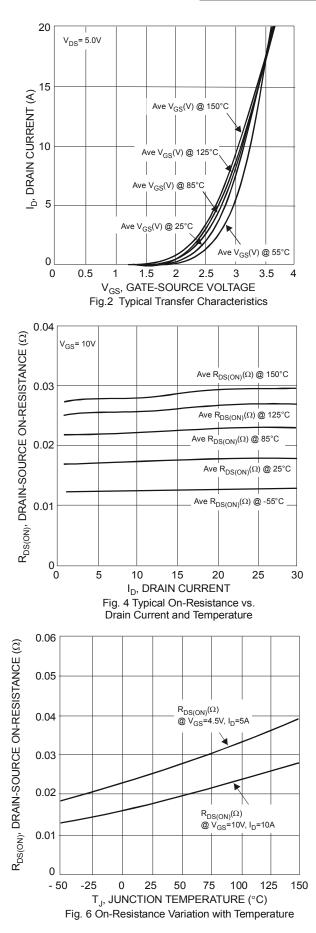
8. I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep T_i=+25°C

9. Short duration pulse test used to minimize self-heating effect.

10. Guaranteed by design. Not subject to product testing.







NEW PRODUCT

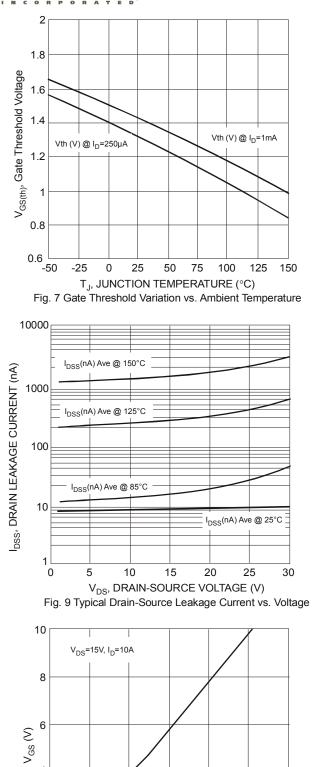
DMG4822SSD Document number: DS35403 Rev. 2 - 2

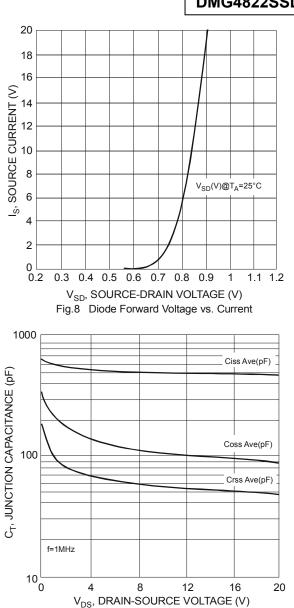


DMG4822SSD Document number: DS35403 Rev. 2 - 2









v_{DS}, DRAIN-SOURCE VOLTAGE (V) Fig. 10 Typical Junction Capacitance

2

4

6

Q_G - (nC) Fig. 11 Gate Charge

8

10

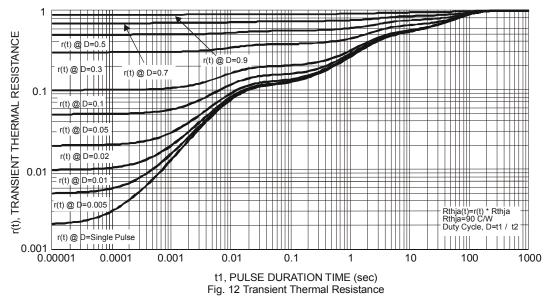
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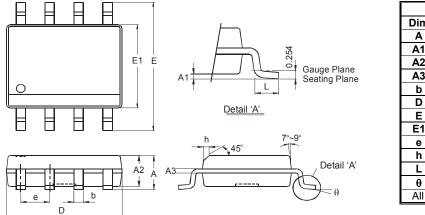
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Package Outline Dimensions

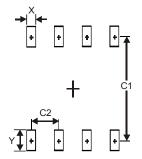
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SO-8				
Dim	Min	Max		
Α	-	1.75		
A1	0.10	0.20		
A2	1.30 1.50			
A3	0.15 0.25			
b	0.3	0.5		
D	4.85	4.95		
ш	5.90	6.10		
E1	3.85	3.95		
e	1.27 Typ			
h	-	0.35		
L	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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